

Day : Wednesday

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Date: 6/8/2005

Time: 14:07:31

Inventor Information for 09/836969

Inventor Name	City	State/Country
JANKO, BOZIDAR	PORTLAND	OREGON
FERGUSON, KEVIN M.	BEAVERTON	OREGON
STRANEY, GALE L.	ALOHA	OREGON
WILLIAMS, GEORGE M.	PORTLAND	OREGON

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Inventor Name Search Result

Your Search was:

Last Name = JANKO

First Name = BOZIDAR

Application#	Patent#	Status	Date Filed	Title	Inventor Name 35
10418405	Not Issued	082	04/18/2003	ATTENTION MODEL ENHANCED VIDEO WAVEFORM MONITOR	JANKO, BOZIDAR
10355391	Not Issued	030	01/31/2003	VIDEO EDITING TIMELINE WITH MEASUREMENT RESULTS	JANKO, BOZIDAR
10355390	Not Issued	030	01/31/2003	PICTURE ANALYZER WITH A WINDOW INTERFACE	JANKO, BOZIDAR
10224956	Not Issued	030	08/20/2002	AUTOMATIC MEASUREMENT OF VIDEO PARAMETERS	JANKO, BOZIDAR
09836969	Not Issued	071	04/17/2001	STREAMING MEDIA QUALITY ANALYZER SYSTEM	JANKO, BOZIDAR
09778184	6633329	150	02/06/2001	FROZEN FIELD DETECTION OF FORMERLY ENCODED VIDEO	JANKO, BOZIDAR
09518430	6671409	150	03/03/2000	BLOCKINESS PERIOD DETECTION OF DCT-BASED CODECS	JANKO, BOZIDAR
09499886	6690840	150	02/08/2000	IMAGE ALIGNMENT WITH GLOBAL TRANSLATION AND LINEAR STRETCH	JANKO, BOZIDAR
09469927	6437821	150	12/22/1999	HARMONIC MEASUREMENT OF BLOCKINESS IN VIDEO SIGNALS	JANKO, BOZIDAR
09457417	6377297	150	12/07/1999	DETECTION OF REPEATED AND FROZEN FRAMES IN A VIDEO SIGNAL	JANKO, BOZIDAR
09457411	6433819	150	12/07/1999	DETECTION OF GAUSSIAN NOISE IN VIDEO SIGNALS	JANKO, BOZIDAR
09152495	6795580	150	09/10/1998	PICTURE QUALITY MEASUREMENT USING BLOCKINESS	JANKO, BOZIDAR

<u>09026758</u>	<u>6075561</u>	150	02/20/1998	LOW DUTY-CYCLE TRANSPORT OF VIDEO REFERENCE IMAGES	JANKO, BOZIDAR
<u>08896912</u>	<u>5940124</u>	150	07/18/1997	ATTENTIONAL MAPS IN OBJECTIVE MEASUREMENT OF VIDEO QUALITY DEGRADATION	JANKO, BOZIDAR
<u>08605241</u>	<u>5818520</u>	150	02/12/1996	PROGRAMMABLE INSTRUMENT FOR AUTOMATIC MEASUREMENT OF COMPRESSED VIDEO QUALITY	JANKO, BOZIDAR
<u>08025699</u>	Not Issued	161	03/03/1993	TIME DOMAIN REFLECTOMETRY INSTRUMENT AND METHOD FOR CHARACTERIZING A SEMICONDUCTOR PACKAGE OR OTHER INTERCONNECT NETWORK	JANKO, BOZIDAR
<u>08025476</u>	<u>5321365</u>	150	03/03/1993	REDUCED NOISE SENSITIVITY IN INVERSE SCATTERING THROUGH FILTERING	JANKO, BOZIDAR
<u>07919494</u>	Not Issued	161	07/24/1992	ADAPTER FOR A CIRCUIT BOARD INTERCONNECT SYSTEM FOR USE WITH SURFACE MOUNTED IC DEVICES	JANKO, BOZIDAR
<u>07811855</u>	<u>5221895</u>	150	12/23/1991	PROBE WITH MICROSTRIP TRANSMISSION LINES	JANKO, BOZIDAR
<u>07720072</u>	<u>5202622</u>	150	06/24/1991	ADAPTER AND TEST FIXTURE FOR AN INTEGRATED CIRCUIT DEVICE PACKAGE	JANKO, BOZIDAR
<u>07530141</u>	<u>5166609</u>	250	05/24/1990	ADAPTER AND TEST FIXTURE FOR AN INTEGRATED CIRCUIT DEVICE PACKAGE	JANKO, BOZIDAR
<u>07484334</u>	<u>5015946</u>	150	02/26/1990	HIGH DENSITY PROBE	JANKO, BOZIDAR
<u>07410197</u>	Not Issued	161	09/21/1989	OPTICAL PROJECTION WORKSTATION	JANKO, BOZIDAR
<u>07338787</u>	<u>4950981</u>	150	04/14/1989	APPARATUS FOR TESTING A CIRCUIT BOARD	JANKO, BOZIDAR
<u>07338786</u>	<u>4963821</u>	150	04/14/1989	PROBE AND METHOD FOR TESTING A POPULATED	JANKO, BOZIDAR

				CIRCUIT BOARD	
<u>07338712</u>	Not Issued	161	04/14/1989	METHOD OF TESTING A CIRCUIT BOARD	JANKO, BOZIDAR
<u>07251046</u>	Not Issued	161	09/26/1988	OPTICAL REFLECTANCE PROBE	JANKO, BOZIDAR
<u>07150795</u>	Not Issued	161	02/01/1988	RAILMOUNT PROBE FIXTURING SYSTEM	JANKO, BOZIDAR
<u>07059662</u>	Not Issued	161	06/08/1987	METHOD AND APPARATUS FOR TESTING UNPACKAGED INTEGRATED CIRCUITS IN A HYBRID CIRCUIT ENVIRONMENT	JANKO, BOZIDAR
<u>07027700</u>	Not Issued	166	03/19/1987	OPTICAL REFLECTANCE PROBE	JANKO, BOZIDAR
<u>06904600</u>	4891585	150	09/05/1986	MULTIPLE LEAD PROBE FOR INTEGRATED CIRCUITS IN WAFER FORM	JANKO, BOZIDAR
<u>06814857</u>	Not Issued	168	12/30/1985	ELECTRONIC PROBE	JANKO, BOZIDAR
<u>06764519</u>	4623819	150	08/12/1985	ACCELERATING AND SCAN EXPANSION LENS MEANS FOR A CATHODE RAY TUBE	JANKO, BOZIDAR
<u>06453447</u>	Not Issued	166	12/27/1982	ACCELERATING AND SCAN EXPANSION ELECTRON LENS SYSTEM	JANKO, BOZIDAR
<u>06038606</u>	4277722	150	05/14/1979	CATHODE RAY TUBE HAVING LOW VOLTAGE FOCUS AND DYNAMIC CORRECTION	JANKO, BOZIDAR

Inventor Search Completed: No Records to Display.

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